Sea	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/656,055	YAVER ET AL.	
Examiner	Art Unit	
lo No Llines	1645	

SEARCHED			
Class	Subclass	Date	Examiner
424	9.2, 94.1, 116, 278.1	2/6/2006	JAH
435	4, 7.2		
	7.31,		
	7.32, 7.4		
	7.95, 32		
	71.3, 243		i
	244,		
	252.1		
	254.1		
	255.1		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
STIC, west, deerwent, biosis, argicola, caplus, japiom eplus, scisearch, medline, blotechno, commerical databases, inventor	2/6/2006	JAH	
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